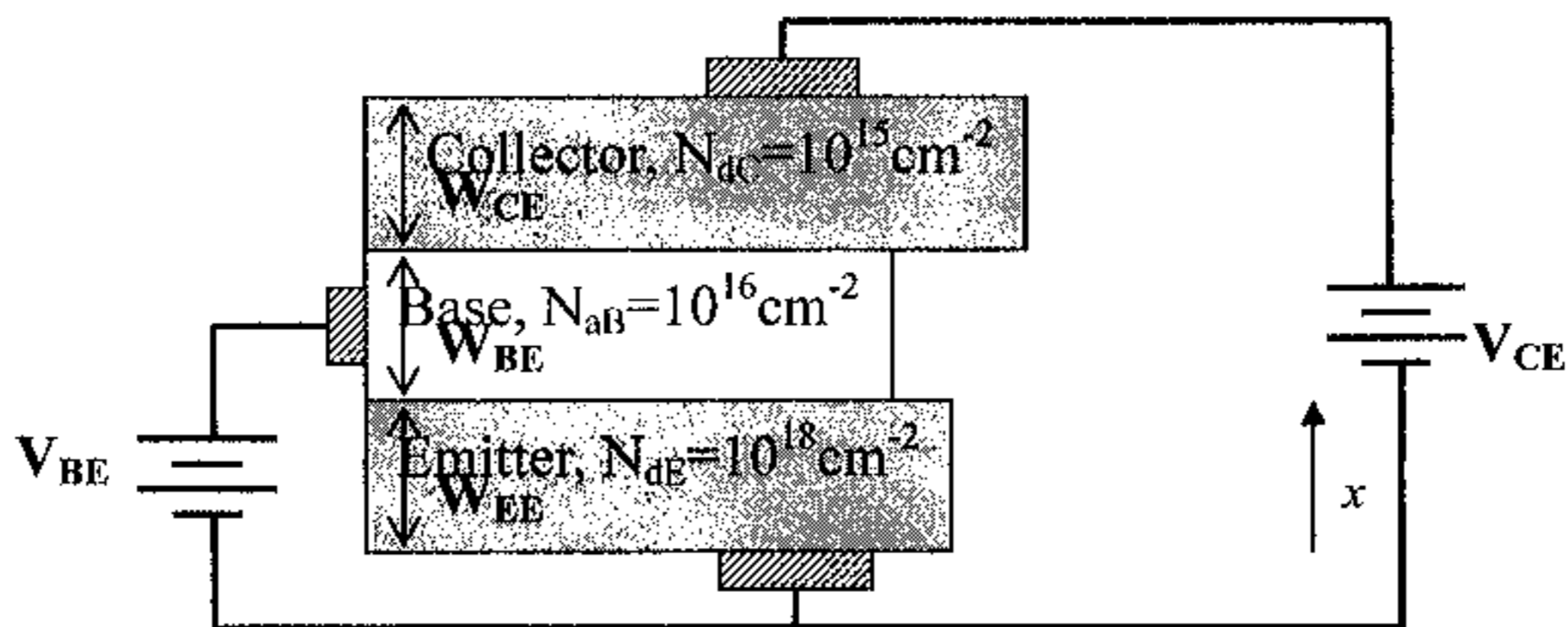


九十二學年度 電子工程研究所 系(所) _____ 組碩士班研究生招生考試

科目 固態電子元件 科號 2605 共 2 頁第 1 頁 *請在試卷【答案卷】內作答

1. For a MOS capacitor fabricated on p-type silicon substrate and with a SiO_2 thickness of d , draw the schematic diagrams of the following items under the condition of strong inversion: (1) energy band diagram of the three materials (metal, SiO_2 , and Si) and mark the conduction band edge E_C , valence band edge E_V , intrinsic Fermi level E_i , and Fermi level E_F of the semiconductor, (2) schematic diagram of the charge distribution, (3) schematic diagram of the electric field distribution, (4) schematic diagram of the electrostatic potential distribution. Use x as the horizontal axis for all the four diagrams. (20%)
2. The threshold voltage of a metal-oxide-semiconductor field effect transistor (MOSFET) is usually expressed as the sum of four terms. (1) Write down the expression of the threshold voltage of a MOSFET. Explain the meaning of each term. (2) For typical n-channel and p-channel MOSFETs, what is the polarity of each term (i.e., whether they are positive or negative)? (15%)
3. A npn BJT with doping level label in the Figure shown below. Let $n_i = 1 \times 10^{10} \text{ cm}^{-3}$, $V_T \ln 10 = 60 \text{ mV}$, $W_E = 0.1 \mu\text{m}$, $W_B = 0.2 \mu\text{m}$, $W_C = 0.5 \mu\text{m}$. Assume ohmic contact at the metal/semiconductor interface. (a) Plot the energy-band diagram, minority carrier densities, $n(x)$ and $p(x)$ and electric field, $E(x)$, at thermal equilibrium when $V_{BE} = V_{CE} = 0$. Label the position of the fermi level and values of $n(x)$, $p(x)$ at the boundaries. (10%) (b) Plot the energy-band diagram, minority carrier densities, $n(x)$ and $p(x)$ and electric field $E(x)$ at thermal equilibrium when $V_{BE} = 0.6 \text{ V}$, $V_{CE} = 1.5 \text{ V}$. Label the position of the fermi level and values of $n(x)$, $p(x)$ at the boundaries. (10%) (c) Discuss respectively how the current gain, β , of this device changes when N_{dB} increases/ W_E increases? (5%)



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科目 固態電子元件 科號 2605 共 2 頁第 2 頁 *請在試卷【答案卷】內作答

4. JFET

- (a) Plot the cross-section of a JFET device that can be realized in CMOS single-well technology on p-type substrate. (5%)
- (b) How will the substrate bias affect the pinch-off voltage, V_p ? (5%)

5. Plot (5%) and explain briefly (10%) the temperature dependence of carrier mobility in semiconductor materials.

6. What is a (a) one-sided junction (5%); (b) linear graded junction (5%); and (c) hyper-abrupt junction (5%)?